

SLOVENSKI STANDARD

SIST EN 62490-1:2010

01-november-2010

Merilna metoda ESL - 1. del: Kondenzatorji s priključnimi izvodi za elektronsko opremo (IEC 62490-1:2010)

ESL measuring method - Part 1: Capacitors with lead terminal for use in electronic equipment (IEC 62490-1:2010)

ESL-Messverfahren - Teil 1: Kondensatoren mit Anschlussdrähten zur Verwendung in Geräten der Elektrotechnik und Elektronik (IEC 62490-1:2010)

Méthode de mesure de l'ESL - Partie 1: Condensateurs à bornes de sortie utilisés dans les équipements électroniques (CEI 62490-1:2010)

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Ta slovenski standard je istoveten z: EN 62490-1:2010

ICS:

31.060.01 Kondenzatorji na splošno Capacitors in general

SIST EN 62490-1:2010

en

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 62490-1

September 2010

ICS 31.060.01

English version

ESL measuring method - Part 1: Capacitors with lead terminal for use in electronic equipment (IEC 62490-1:2010)

Méthode de mesure de l'ESL -
Partie 1: Condensateurs à bornes
de sortie utilisés dans les équipements
électroniques
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ESL-Messverfahren -
Teil 1: Kondensatoren
mit Anschlussdrähten zur Verwendung
in Geräten der Elektrotechnik
und Elektronik
(IEC 62490-1:2010)

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This European Standard was approved by CENELEC on 2010-09-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 40/2044/FDIS, future edition 1 of IEC 62490-1, prepared by IEC TC 40, Capacitors and resistors for electronic equipment, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62490-1 on 2010-09-01.

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The following dates were fixed:

- latest date by which the EN has to be implemented
at national level by publication of an identical
national standard or by endorsement (dop) 2011-06-01
- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2013-09-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 62490-1:2010 was approved by CENELEC as a European Standard without any modification.

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Annex ZA
(normative)**Normative references to international publications
with their corresponding European publications**

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60384-1	2008	Fixed capacitors for use in electronic equipment - Part 1: Generic specification	EN 60384-1	2009

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

ESL measuring method –
Part 1: Capacitors with lead terminal for use in electronic equipment

Méthode de mesure de l'ESL –
Partie 1: Condensateurs à bornes de sortie utilisés dans les équipements électroniques

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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	5
4 Measurement jig, short compensation jig, and spacer.....	5
4.1 Measurement jig (test fixture)	5
4.2 Short compensation jig	5
4.3 Spacer	6
5 Measuring method.....	7
5.1 Measuring instrument.....	7
5.2 Measurement conditions.....	7
5.3 Preparation of sample	8
5.4 Measurement points	8
5.5 Frequency and signal level.....	8
5.6 Measurement procedure.....	8
5.6.1 General	8
5.6.2 Open compensation.....	9
5.6.3 Short compensation.....	9
5.6.4 ESL measurement	9
6 Items to be indicated in test result report.....	10
Annex A (informative) The basic concept on ESL measuring method	11
Figure 1 – Short compensation jig.....	6
Figure 2 – Constructional example of the short compensation spacer and the measurement spacer	7
Figure 3 – Measure points: seating plane or flange of capacitor on the printed circuit board	8
Figure 4 – Method of short compensation	9
Figure 5 – Example in state where electrode of measurement jig shifted.....	10
Figure A.1 – Fundamental view of ESL measurement	11

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ESL MEASURING METHOD –

Part 1: Capacitors with lead terminal
for use in electronic equipment

FOREWORD

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International Standard IEC 62490-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

The text of this standard is based on the following documents:

FDIS	Report on voting
40/2044/FDIS	40/2056/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 62490 series, under the general title *ESL measuring method*, can be found on the IEC website.